

## **Search Notes**



**Application/Control No.**

10/705,235

Examiner

John P. Sheehan

**Applicant(s)/Patent under  
Reexamination**

SHIMADA ET AL.

Art Unit

1742

**SEARCHED**

## **SEARCH NOTES (INCLUDING SEARCH STRATEGY)**

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner